

R.I.T

College of Science

Chester F. Carlson

Center for **IMAGING** SCIENCE

Seminar Series

Sinc Func. Seeks Meaningful Relationship with CCD...

or, MTF for Critical Imaging

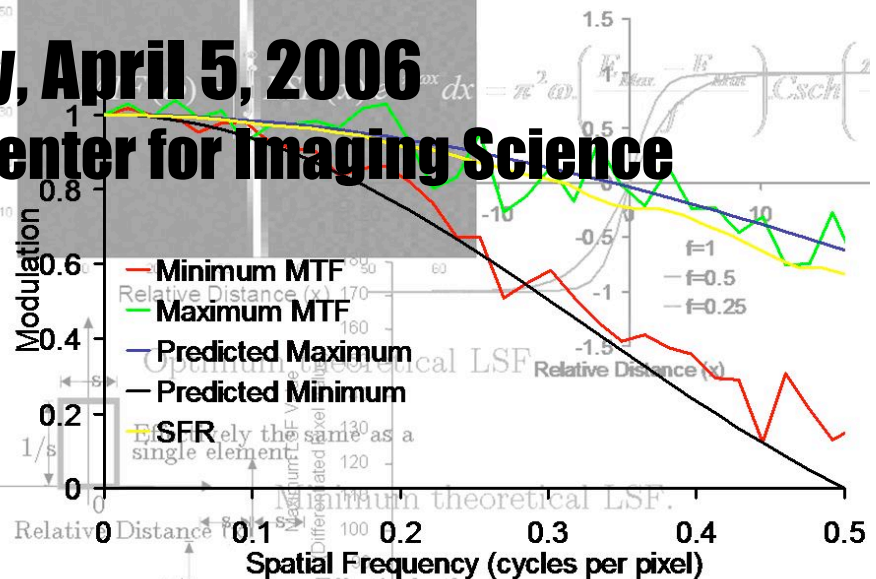
Robin Jenkin

Lecturer in Electro-Optics, Cranfield University, UK

4pm, Wednesday, April 5, 2006

Auditorium of the Center for Imaging Science

During the talk, there will be a Contest and Drawing for Student Membership in the Royal Photographic Society



Digital imaging is being increasingly accepted as a solution for critical systems. During this presentation, we will demonstrate that the Sinc function is overly optimistic when used to describe the MTF of discrete arrays. We will derive a novel pessimistic formula for digital imaging array MTF. We will then tame this beast and demonstrate its measurement using simple modification of ISO 12233 via measurements of a commercially available camera and a Monte-Carlo simulation.

www.cis.rit.edu/seminar

for up-to-date seminar schedule, video archives and abstracts.

Speaker Bio

Robin Jenkin received BS and PhD degrees in the field of imaging science from the University of Westminster in 1995 and 2001 respectively. He also holds MS in Computer Vision and Image Processing from University College London, 1996. Robin currently lectures in the field of Electro-Optics for Cranfield University, UK on subjects in defense imaging. Robin is Executive Editor of The Imaging Science Journal of the Royal Photographic Society, the UK's oldest journal dedicated to imaging science. Robin's research interests are varied. They include the relationship between objective measures of image quality and its relationship to the ability to complete varied tasks.